



INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT

FORM PTO-1449

ATTY. DOCKET NO.  
20110/00401

SERIAL NO.  
10/090,102

APPLICANT(S)  
Alex G. ZEIF

FILING DATE  
March 2, 2002

GROUP  
2161 2857

U. S. PATENT DOCUMENTS

EXAMINER INITIAL	PATENT NUMBER	PATENT DATE	NAME	CLASS	SUBCLASS	FILING DATE
POP	4,956,783	September 11, 1990	Teranishi et al.	RECEIVED DEC 13 2002 Technology Center 2100		
	5,479,361	December 26, 1995	Kurtzberg et al.			
	5,862,054	January 19, 1999	Li	RECEIVED DEC 13 2002 Technology Center 2100		
	5,896,293	April 20, 1999	Teramoto et al.			
	5,946,661	August 31, 1999	Rothschild et al.	RECEIVED DEC 13 2002 Technology Center 2100		
	6,038,486	March 14, 2000	Saitoh et al.			
	6,115,643	September 5, 2000	Stine et al.	RECEIVED DEC 13 2002 Technology Center 2100		
	6,128,540	October 3, 2000	Van Der Vegt et al.			
	6,211,905	April 3, 2001	Rudt et al.	RECEIVED DEC 13 2002 Technology Center 2100		
	6,249,715	June 19, 2001	Yuri et al.			
	6,381,509	April 30, 2002	Thiel et al.	RECEIVED DEC 13 2002 Technology Center 2100		
POP	6,415,191	July 2, 2002	Pryor			

U. S. PATENT APPLICATION PUBLICATIONS

EXAMINER INITIAL	PUBLICATION NUMBER	PUBLICATION DATE	NAME	CLASS	SUBCLASS	FILING DATE
POP	2001/0025225	September 27, 2001	Ota et al.			
POP	2002/0071603	June 13, 2002	Ungpiyakul et al.			

OTHER DOCUMENTS

EXAMINER INITIAL	AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.
POP	Hersh Kohli et. al, E-manufacturing Software for Product and Process Real-time Monitoring, 5 pages, <a href="http://www.manufacturingpulse.com/news_events/smta_oct_2001_manufacturing_pulse.pdf">http://www.manufacturingpulse.com/news_events/smta_oct_2001_manufacturing_pulse.pdf</a>
POP	Gensym Corp., Real-time Monitoring Diagnosis, Control and Process Optimization, 3 pages <a href="http://www.gensym.com/manufacturing/">http://www.gensym.com/manufacturing/</a>
POP	Syscon Int'l, Inc., Data Collection Modules, 4 pages, <a href="http://www.syscon-plantstar.com/literature/dcm.pdf">http://www.syscon-plantstar.com/literature/dcm.pdf</a>

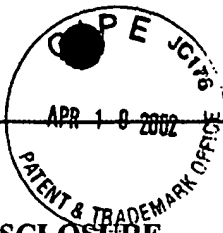
EXAMINER

*Pat* *Q*

DATE CONSIDERED

11/5/07

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**U. S. PATENT DOCUMENTS**

EXAMINER INITIAL	PATENT NUMBER	PATENT DATE	NAME	CLASS	SUBCLASS	FILING DATE
POP	4,718,025	January 5, 1988	Minor et al.			
	4,802,094	January 31, 1989	Nakamura et al.			
	5,586,041	December 17, 1996	Mangrulkar			
	5,691,895	November 25, 1997	Kurtzberg et al.			
	5,821,990	October 13, 1998	Rudt et al.			
	5,970,476	October 19, 1999	Fahey			
	6,115,643	September 5, 2000	Stine et al.			
	6,144,885	November 7, 2000	Scarrah			
POP	6,295,510 B1	September 25, 2001	Discenzo			

**FOREIGN PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NUMBER	DATE (M/D/Y)	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

**OTHER DOCUMENTS**

EXAMINER INITIAL		AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.

EXAMINER	<i>Btk</i>	DATE CONSIDERED	11/5/07
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